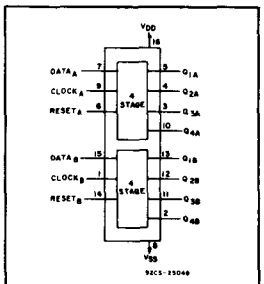
CMOS Dual 4-Stage Static Shift Register

With Serial Input/Parallel Output

The RCA-CD4015A consists of two identical, independent, 4-stage serial-input/parallel-output registers. Each register has independent CLOCK and RESET inputs as well as a single serial DATA input. "Q" outputs are available from each of the four stages on both registers. All register stages are D-type, master-slave flip-flops. The logic level present at the DATA input is transferred into the first register stage and shifted over one stage at each positive-going clock transition.

Resetting of all stages is accomplished by a high level on the reset line. Register expansion to 8 stages using one CD4015A package, or to more than 8 stages using additional CD4015A's is possible.

These types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), 16-lead ceramic flat packages (K suffix), and in chip form (H suffix).



CD4015A
FUNCTIONAL DIAGRAM

MAXIMUM RATINGS, *Absolute-Maximum Values:*

STORAGE-TEMPERATURE RANGE (T_{stg}) . . . . . -65 to +150°C

OPERATING-TEMPERATURE RANGE (T_A):

PACKAGE TYPES D, F, K, H . . . . . -55 to +125°C

PACKAGE TYPE E . . . . . -40 to +85°C

DC SUPPLY-VOLTAGE RANGE, (V_{DD})

(Voltages referenced to V_{SS} Terminal) . . . . . -0.5 to +15 V

POWER DISSIPATION PER PACKAGE (P_D)

FOR T_A = -40 to + 60°C (PACKAGE TYPE E) . . . . . 500 mW

FOR T_A = +60 to +85°C (PACKAGE TYPE E) . . . . . Derate Linearly at 12mW/°C to 200 mW

FOR T_A = -55 to +100°C (PACKAGE TYPES D, F, K) . . . . . 500 mW

FOR T_A = +100 to +125°C (PACKAGE TYPES D, F, K) . . . Derate Linearly at 12 mW/°C to 200 mW

DEVICE DISSIPATION PER OUTPUT TRANSISTOR

FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (ALL PACKAGE TYPES) . . . . 100 mW

INPUT VOLTAGE RANGE, ALL INPUTS . . . . . -0.5 to V_{DD} +0.5 V

LEAD TEMPERATURE (DURING SOLDERING):

At distance 1/16 ± 1/32 inch (1.59 ± 0.79 mm) from case for 10 s max. . . . . +265°C

RECOMMENDED OPERATING CONDITIONS *at T_A = 25°C, Except as Noted.*
For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V_{DD} (V)	LIMITS				UNITS
		D, F, K, H PACKAGES		E PACKAGE		
		MIN.	MAX.	MIN.	MAX.	
Supply-Voltage Range (For T_A = Full Package-Temperature Range)		3	12	3	12	V
Data Setup Time, t_S	5 10	350 80	– –	500 100	– –	ns
Clock Pulse Width, t_W	5 10	500 175	– –	830 200	– –	ns
Clock Input Frequency, f_{CL}	5 10	dc dc	1 3	dc dc	0.6 2.5	MHz
Clock Rise and Fall Time, t_rCL, t_fCL*	5 10	– –	15 5	– –	15 5	μs
Clock Reset Pulse Width, t_W	5 10	500 175	– –	830 200	– –	ns

*If more than one unit is cascaded t_rCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

Features:

- **Medium speed operation . . . . . 5 MHz (typ.) clock rate at $V_{DD} - V_{SS}$ = 10V**
- **Fully static operation**
- **8 master-slave flip-flops plus output buffering**
- **Quiescent current specified to 15 V**
- **Maximum input leakage current of 1 μA at 15 V (full package-temperature range)**
- **1-V noise margin (full package-temperature range)**

Applications:

- **Serial-input/parallel-output data queueing**
- **Serial to parallel data conversion**
- **General-purpose register**

TRUTH TABLE

CL▲	D	R	Q_1	Q_n
⌐⌐	0	0	0	Q_{n-1}
⌐⌐	1	0	1	Q_{n-1}
⌐⌐	X	0	Q_1	Q_n (NO CHANGE)
X	X	1	0	0

▲ = LEVEL CHANGE
X = DON'T CARE CASE

Fig. 1 – Truth table.

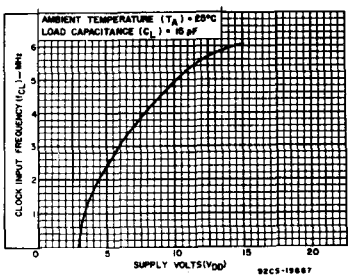


Fig. 2 – Typical clock input frequency vs. supply voltage.

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTICS	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)								UNITS
				D, F, K, H PACKAGES				E PACKAGE				
	V_O (V)	V_{IN} (V)	V_{DD} (V)	-55	+25 TYP.	+25 LIMIT	+125	-40	+25 TYP.	+25 LIMIT	+85	
Quiescent Device Current, I_L Max.	–	–	5	5	0.5	5	300	50	0.5	50	700	μA
	–	–	10	10	1	10	600	100	1	100	1400	
	–	–	15	50	1	50	2000	500	5	500	5000	
Output Voltage: Low Level, V_{OL}	–	5	5	0 Typ.; 0.05 Max								V
	–	10	10	0 Typ.; 0.05 Max								
High Level V_{OH}	–	0	5	4.95 Min.; 5 Typ.								
	–	0	10	9.95 Min.; 10 Typ.								
Noise Immunity: Inputs Low, V_{NL}	4.2	–	5	1.5 Min.; 2.25 Typ.								V
	9	–	10	3 Min.; 4.5 Typ.								
Inputs High V_{NH}	0.8	–	5	1.5 Min.; 2.25 Typ.								
	1	–	10	3 Min.; 4.5 Typ.								
Noise Margin: Inputs Low, V_{NML}	4.5	–	5	1 Min.								V
	9	–	10	1 Min.								
Inputs High, V_{NMH}	0.5	–	5	1 Min.								
	1	–	10	1 Min.								
Output Drive Current: N-Channel (Sink), I_DN Min.	0.5	–	5	0.15	0.3	0.12	0.085	0.072	0.3	0.06	0.05	mA
	0.5	–	10	0.31	0.5	0.25	0.175	0.12	0.5	0.1	0.08	
P-Channel (Source): I_DP Min.	4.5	–	5	-0.1	-0.16	-0.08	-0.055	-0.06	-0.16	-0.05	-0.04	
	9.5	–	10	-0.25	-0.44	-0.20	-0.14	-0.12	-0.44	-0.1	-0.08	
Input Leakage Current, I_{IL}, I_{IH}	Any Input											μA
	–	–	15	$\pm 10^{-5}$ Typ., ±1 Max.								

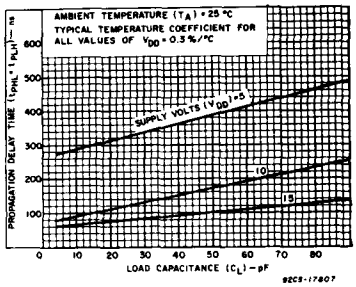


Fig. 3. – Typical propagation-delay time vs. load capacitance.

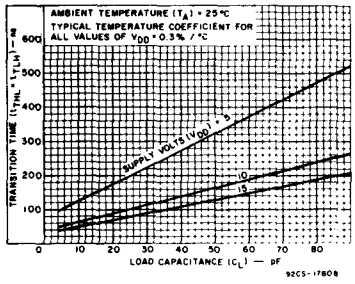


Fig. 4 – Typical transition time vs load capacitance.

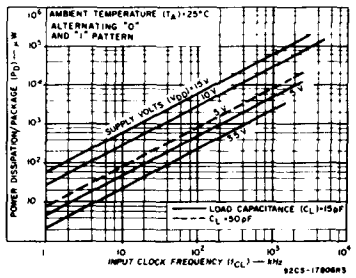


Fig. 5 – Typical dissipation characteristics.

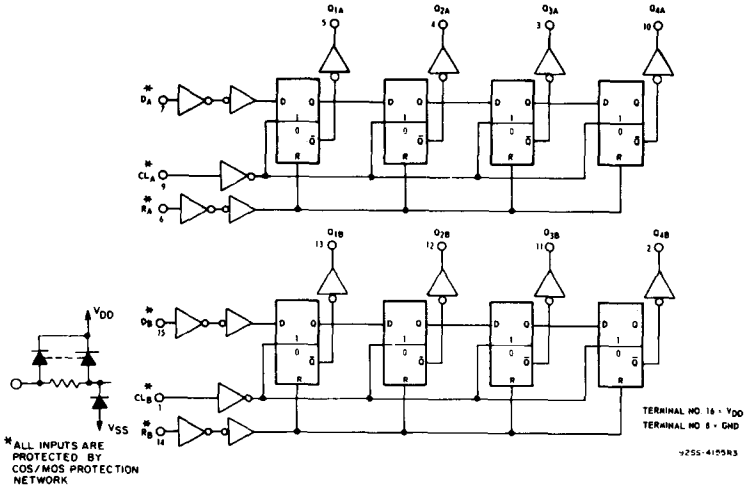


Fig. 6 – Logic diagram.

DYNAMIC ELECTRICAL CHARACTERISTICS

at T_A = 25°C, Input t_r, t_f = 20 ns, C_L = 15 pF, R_L = 200 kΩ

CHARACTERISTIC	TEST CONDITIONS V_{DD} (V)	LIMITS D, F, K, H PACKAGES MIN.	TYP.	MAX.	LIMITS E PACKAGE MIN.	TYP.	MAX.	UNITS
CLOCKED OPERATION								
Propagation Delay Time; T_{PLH}, T_{PHL}	5	–	300	750	–	300	1000	ns
	10	–	100	225	–	100	300	
Transition Time; t_{THL}, t_{TLH}	5	–	150	300	–	150	400	ns
	10	–	75	125	–	75	150	
Minimum Clock Pulse Width, t_W	5	–	200	500	–	200	830	ns
	10	–	100	175	–	100	200	
Clock Rise & Fall Time; t_rCL, t_fCL*	5	–	–	15	–	–	15	μs
	10	–	–	5	–	–	5	
Minimum Data Set-up Time, t_S	5	–	100	350	–	100	500	ns
	10	–	50	80	–	50	100	
Maximum Clock Input Frequency, f_{CL}	5	1	2.5	–	0.6	2.5	–	MHz
	10	3	5	–	2.5	5	–	
Average Input Capacitance, C_I		–	5	–	–	5	–	pF
RESET OPERATION								
Propagation Delay Time, T_{PHL}	5	–	300	750	–	300	1000	ns
	10	–	100	225	–	100	300	
Minimum Reset Pulse Width t_W	5	–	200	500	–	200	830	ns
	10	–	100	175	–	100	200	

*If more than one unit is cascaded t_rCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitve load.

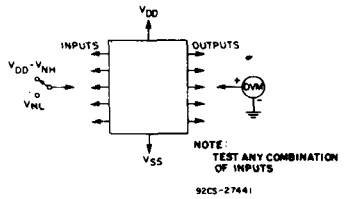


Fig. 7 — Noise-immunity test circuit.

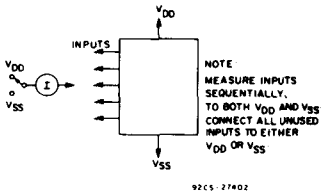
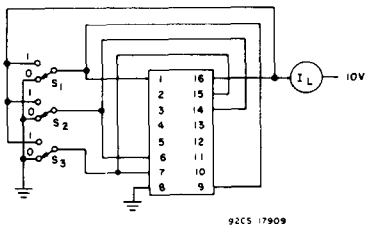


Fig. 8 — Input-leakage-current test circuit.



Test performed with the following sequence of "1's" and "0's"

	S_1	S_2	S_3
Test	0	1	0
Don't Test	0	0	1
Don't Test	1	0	1
Don't Test	0	0	0
Don't Test	1	0	0
Don't Test	0	0	1
Test	1	0	1
Don't Test	0	0	0
Test	1	0	0

Fig. 9 — Quiescent-device-current test circuit.

TERMINAL DIAGRAM

Top View